

**Search Notes**

Application/Control No.

10/020,927

Examiner

Feben M. Haile

Applicant(s)/Patent under  
Reexamination

YAMAGUCHI ET AL.

Art Unit

2663

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: divide, spit, segment, disassemble, packet, data, error, CRC, encode, code, ARQ, retransmit	9/29/2005	FH